



# Alüminyum Test Eğitim ve Araştırma Merkezi

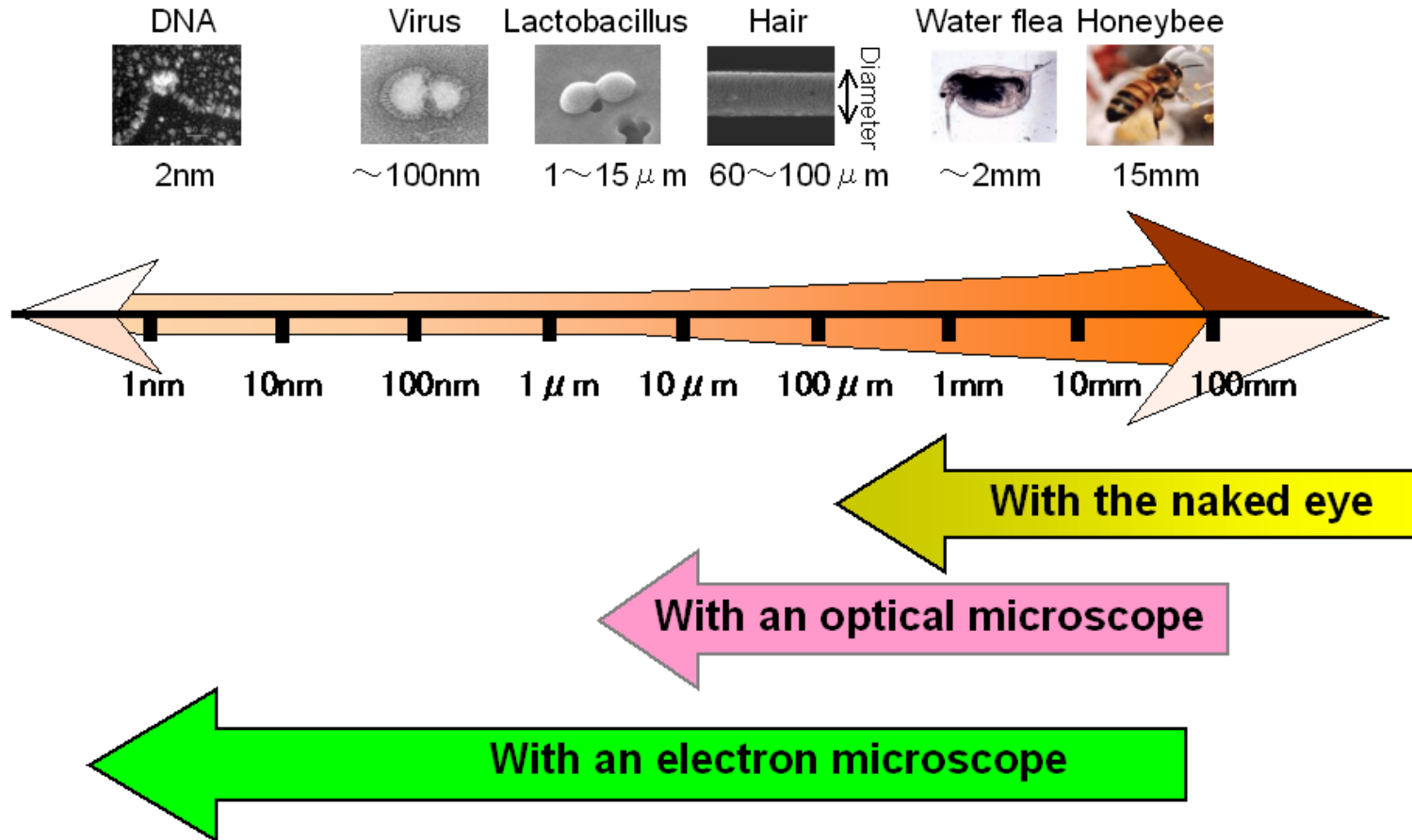
Mart 2017



# SEM Nedir?

# SEM ile Neler Yapılabilir?

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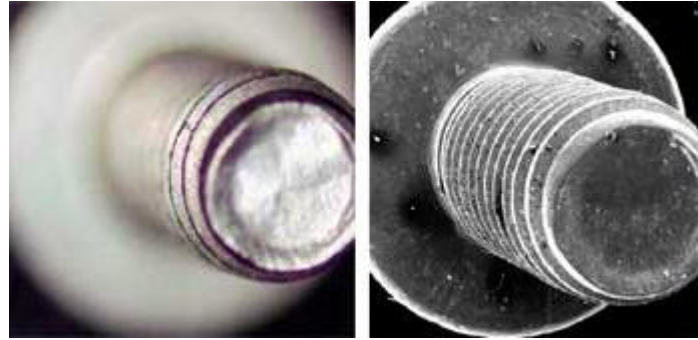


## SEM nedir?

Mikro ve nano boyuttaki yapıları görüntüleyebilmek için kullanılan bir mikroskop türüdür.

- Yüksek ayırt edebilme gücü
  - Yüksek alan derinliği
- } “Büyük” ve “pürüzlü” örnekler, toz halindeki örnekler.

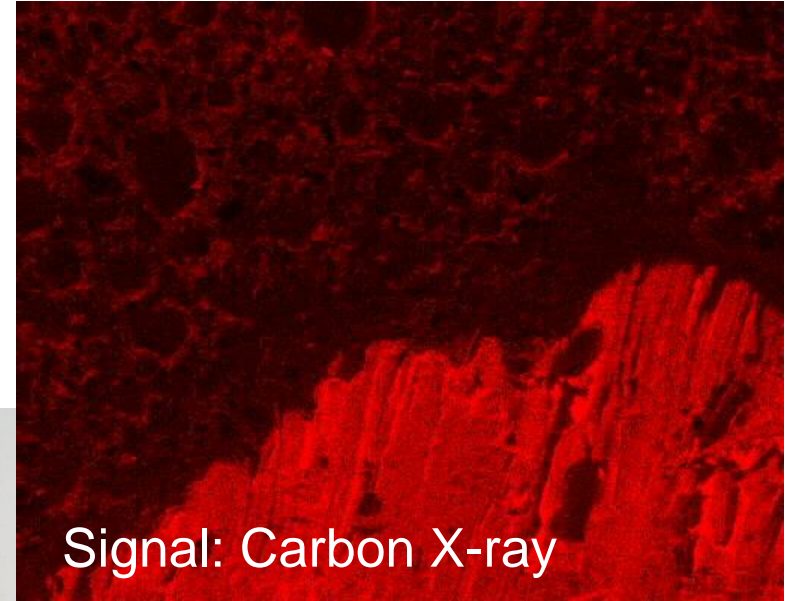
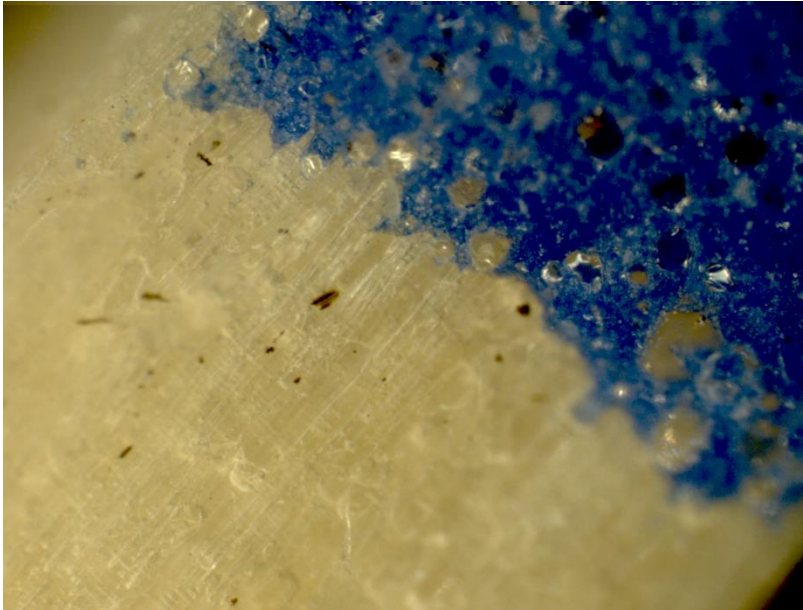
## Optik Mikroskop - SEM

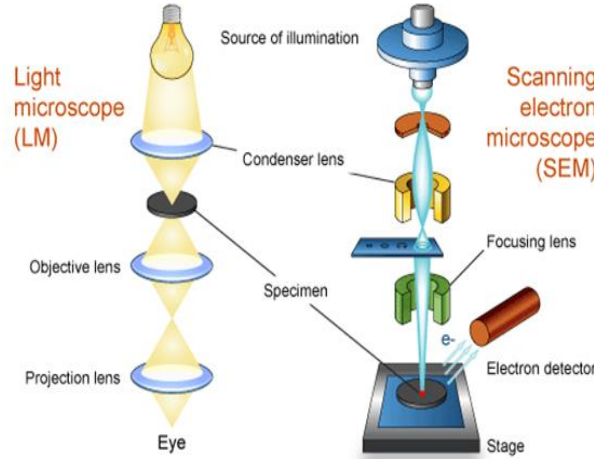
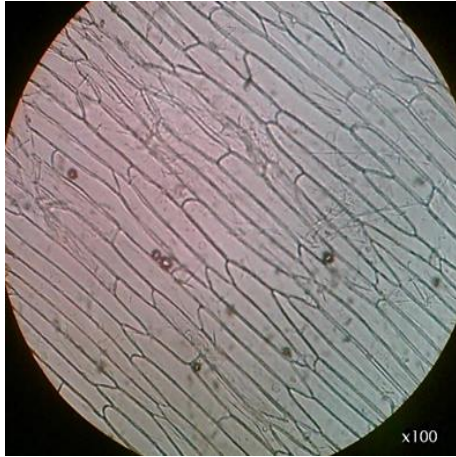


Vida Uzunluğu: ~ 0.6 cm

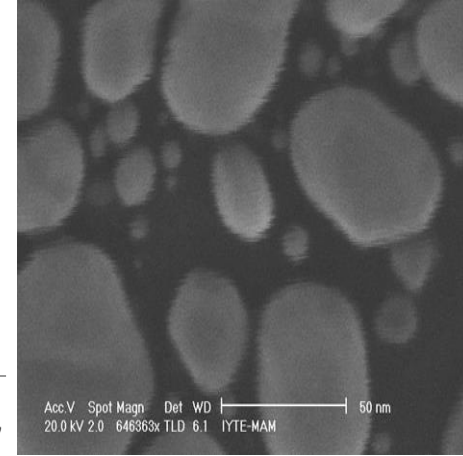
- Topografi, morfoloji ve kimyasal analiz

# Daha iyi alan derinliđi



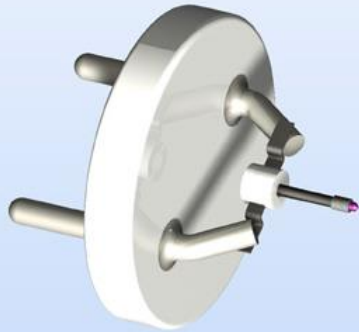


$$r = \frac{0.61\lambda}{\mu \sin \alpha}$$

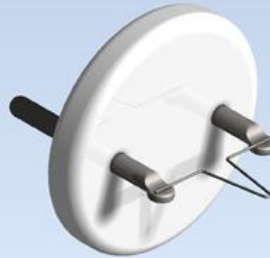


Optik Mikroskop	Elektron Mikroskobu
$\lambda = 400 - 780 \text{ nm}$	$\lambda = 0.00698 - 0.0867 \text{ nm}$
$\mu \geq 1$	$\mu = 1$ (vacuum)
max. $r = 150 \text{ nm}$	for $\lambda = 0.00698 \text{ nm}$ and $\alpha = 0.1$ radians $r = 0.04 \text{ nm}$

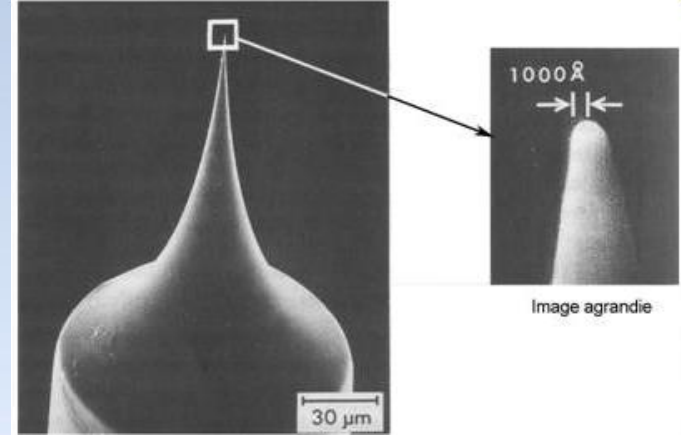
- Termoiyonik kaynaklar (Tungsten filament, LaB6, CeB6)
- Alan emisyonlu kaynaklar (Ekstra vakum ve soğutucu) yüksek akım yoğunlukları
  - Schottky Emitörleri
  - Soğuk Alan Emitörleri



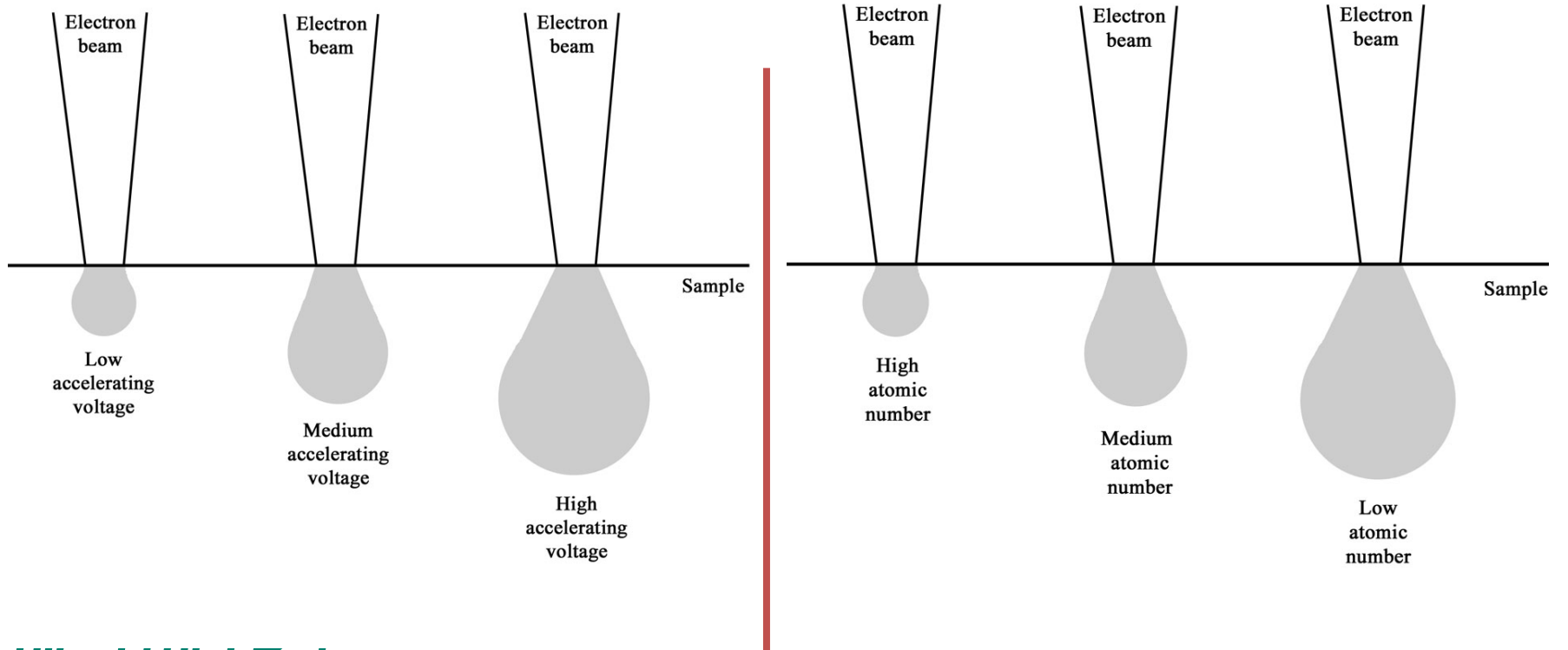
LaB6 Tek kristal



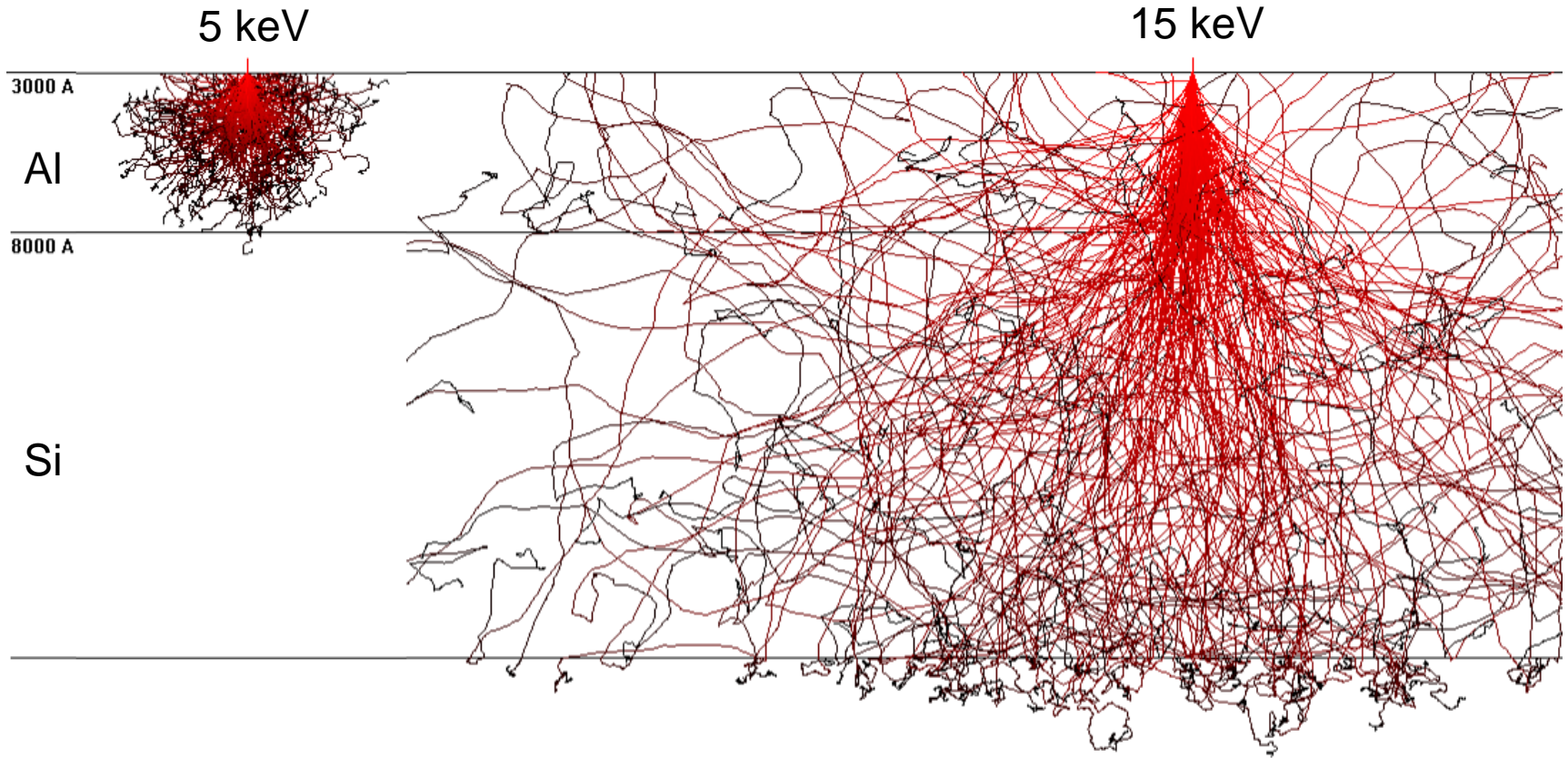
Tungsten filament



Alan emisyonlu kaynak

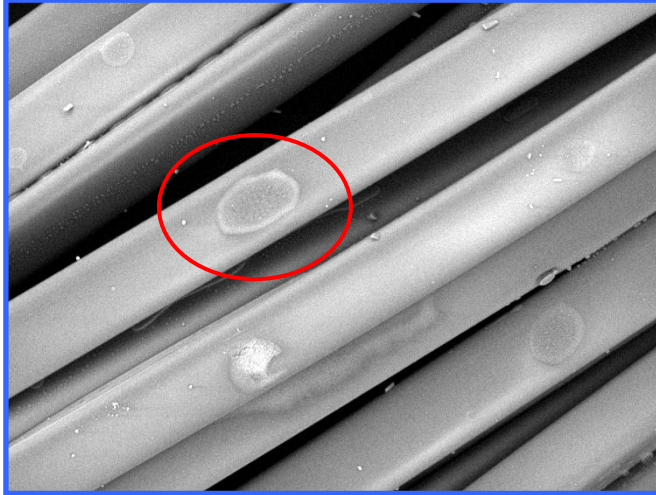
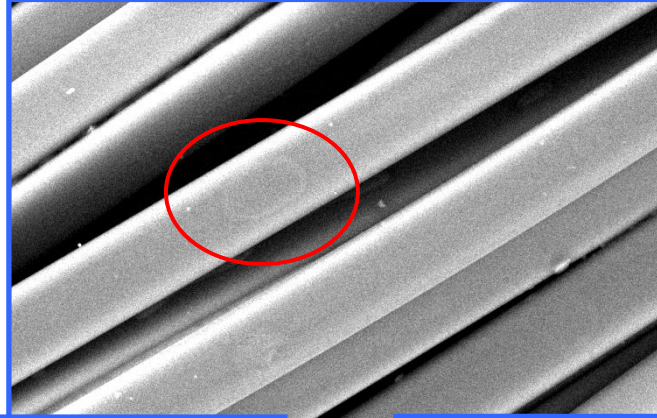




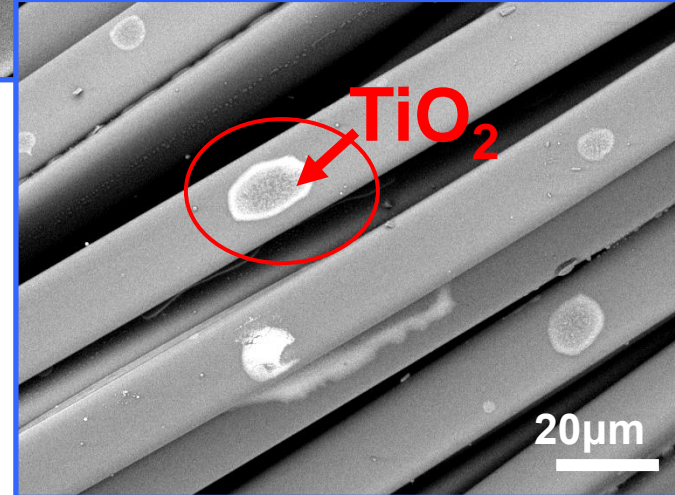


Düşük Enerji ile yüzey detayları

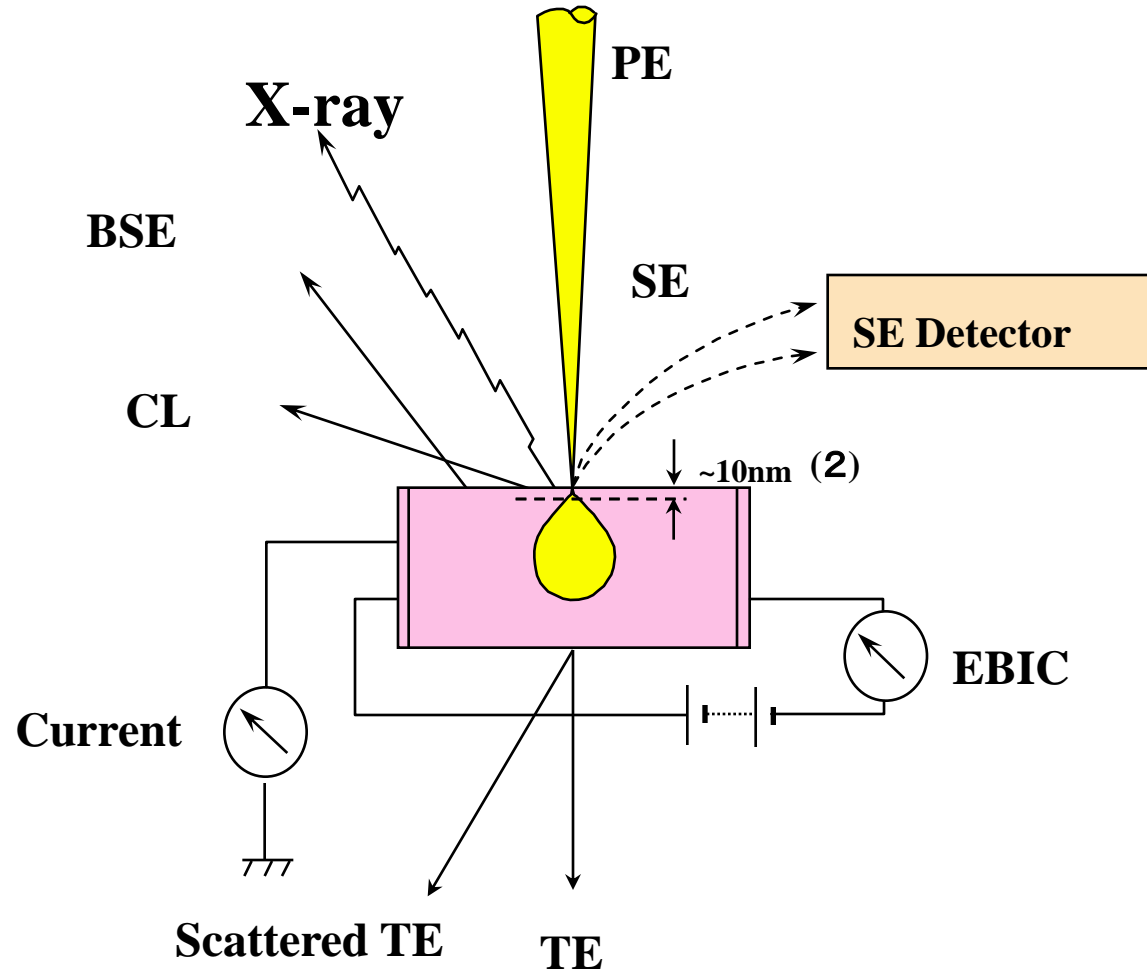
Vacc. : 15kV



Vacc. : 5kV



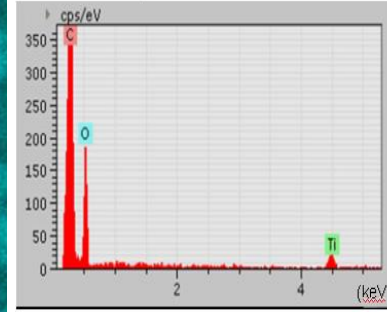
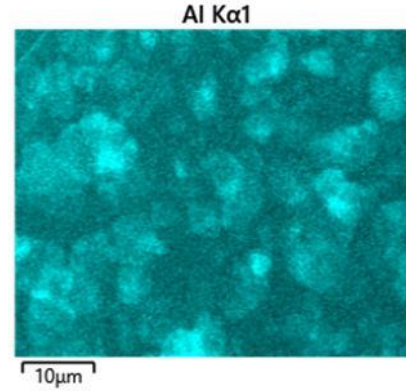
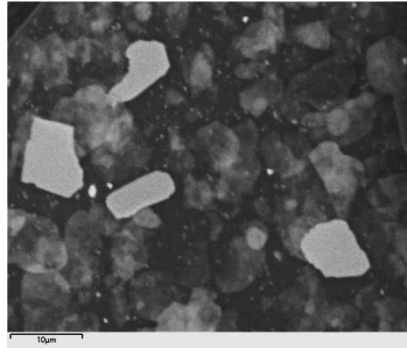
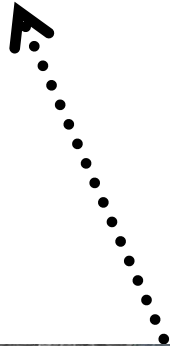
Vacc. : 3kV



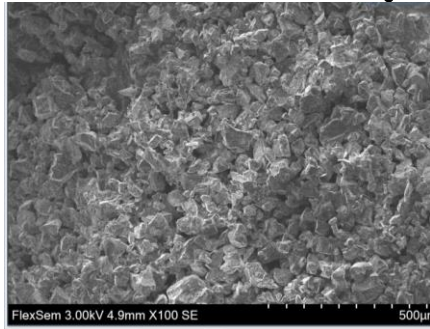
Gelen elektronlar

İkincil elektronlar

Geri saçılmış elektronlar

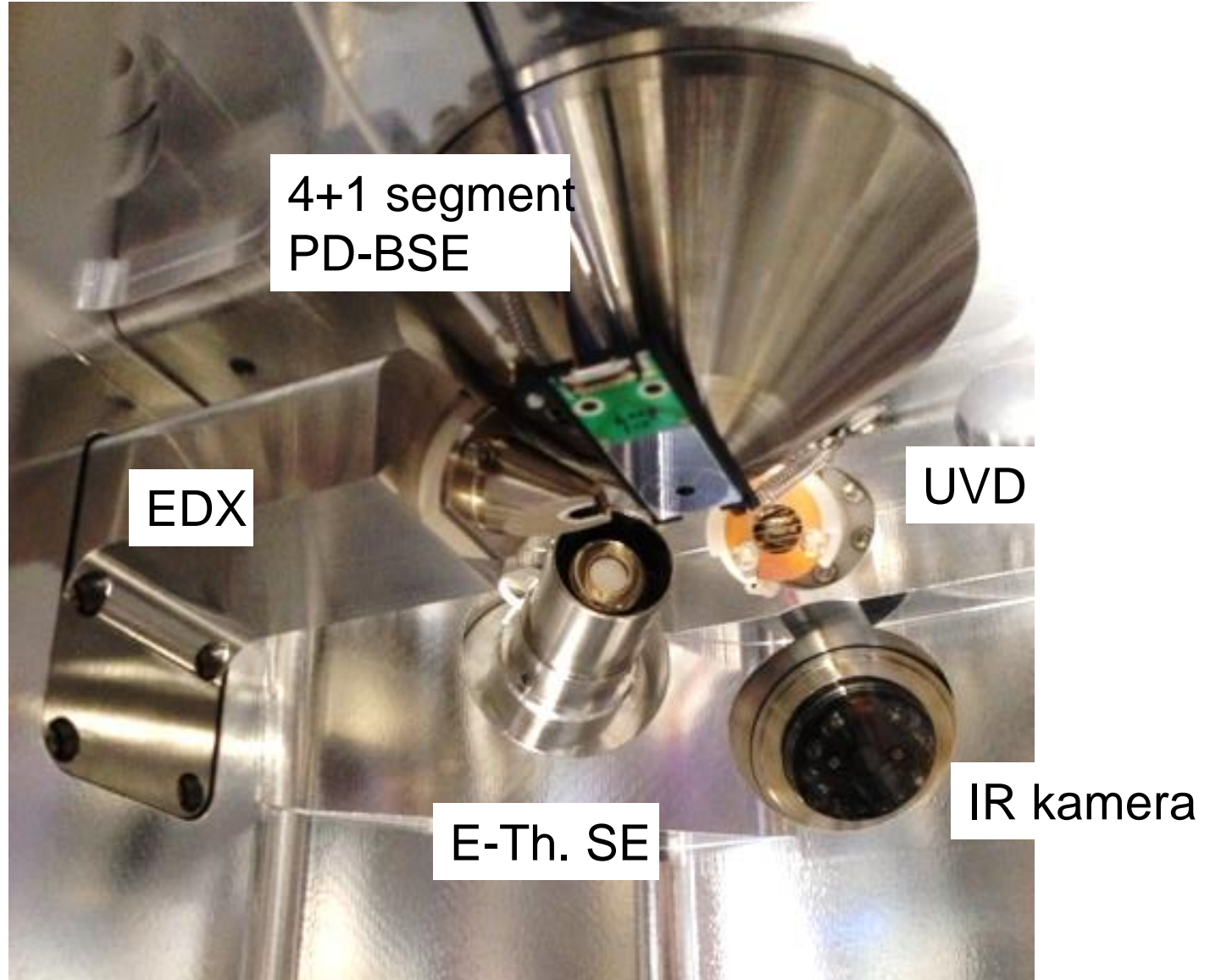


X-ışınları



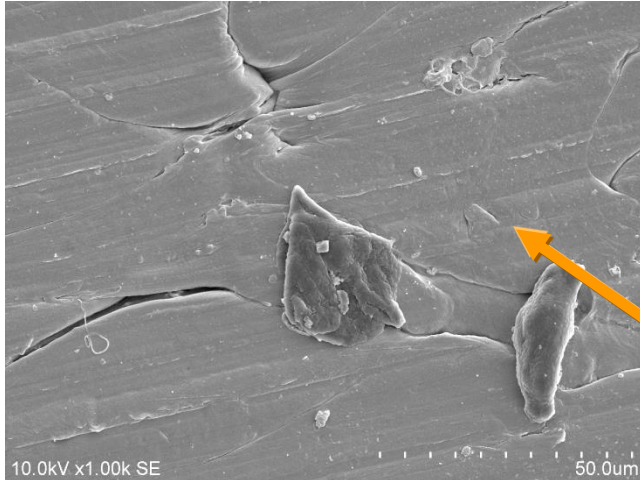
Örnek



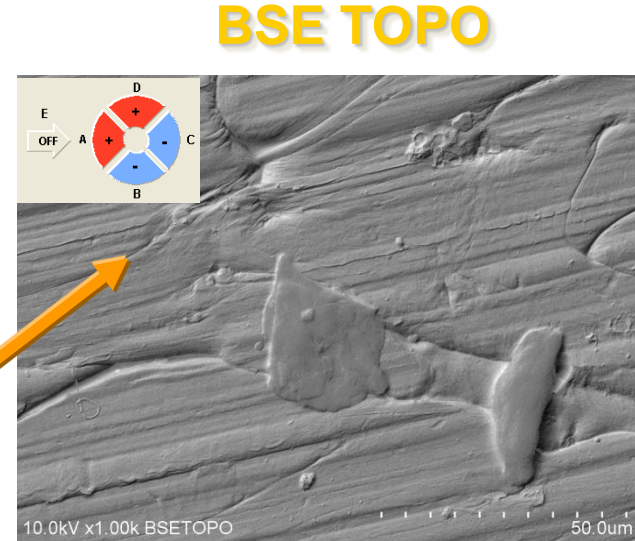


- Everhart-Thornley Dedektörü (SE)
  - İkincil elektronları algılar
  - Sadece yüksek vakum modunda çalışır
- 4+1 segment PD-BSE detektör
  - Geri saçılımlı elektronları algılar
  - 5 segmentli olan dedektör 1.5kV den itibaren görüntü alabilir
  - Düşük vakum, yüksek vakum modlarında çalışır
- Ultra Variable pressure mode Detector (UVD)
  - Düşük vakum modu için foton bazlı SE detektör
  - Düşük vakumdaki soft örneklerin görüntülenmesi

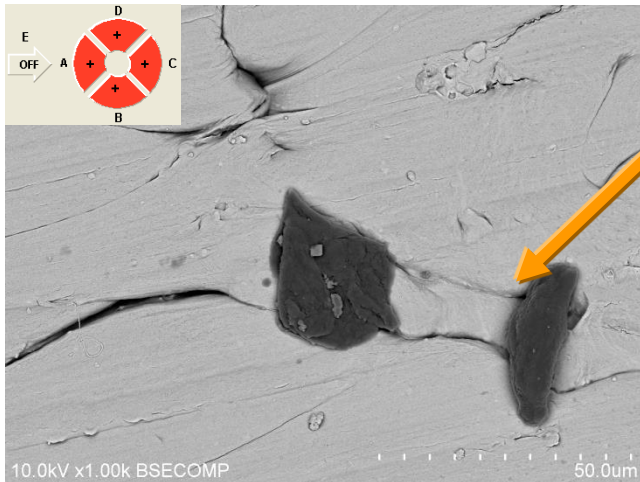
# BSE Detektörü



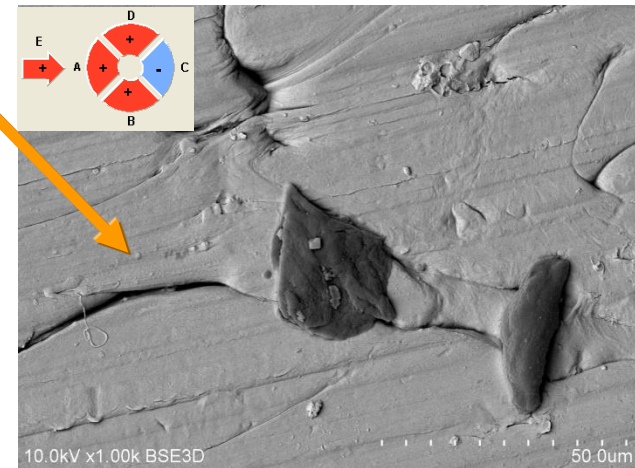
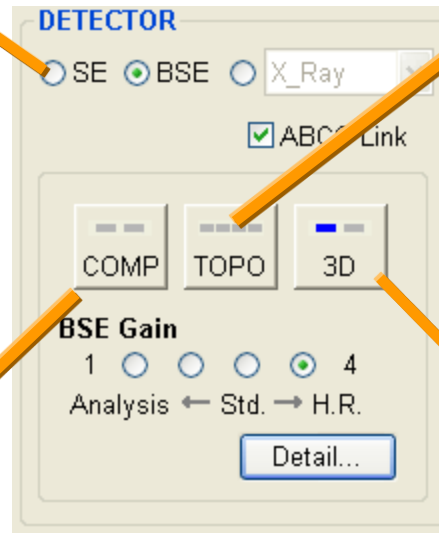
**SE**  
 (Everhart Thornley)



**BSE TOPO**



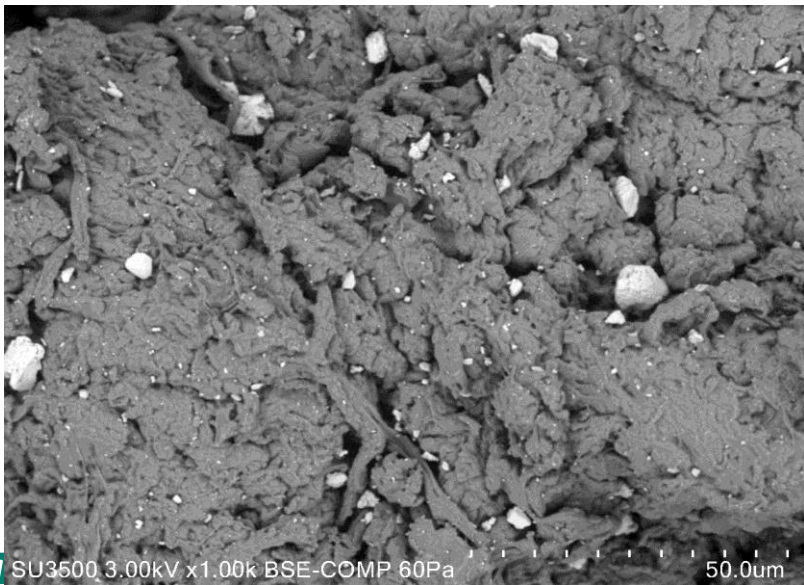
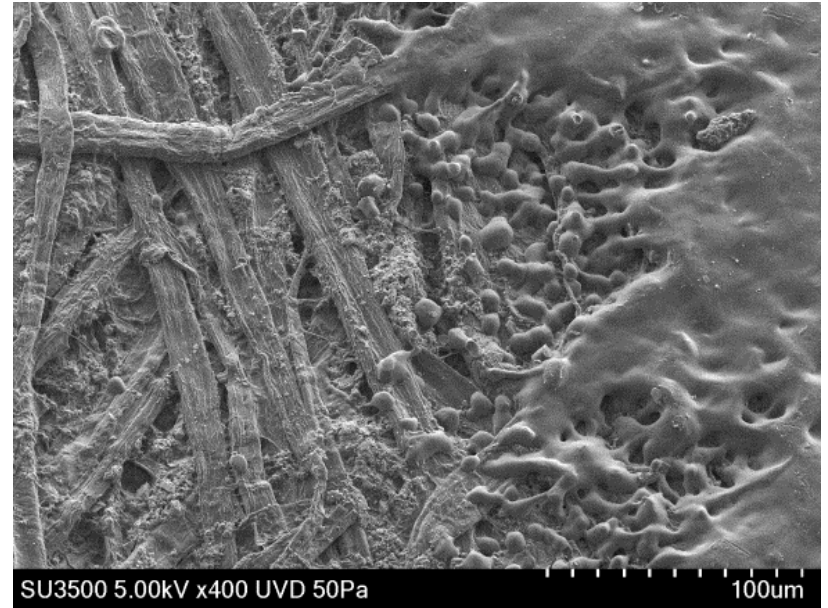
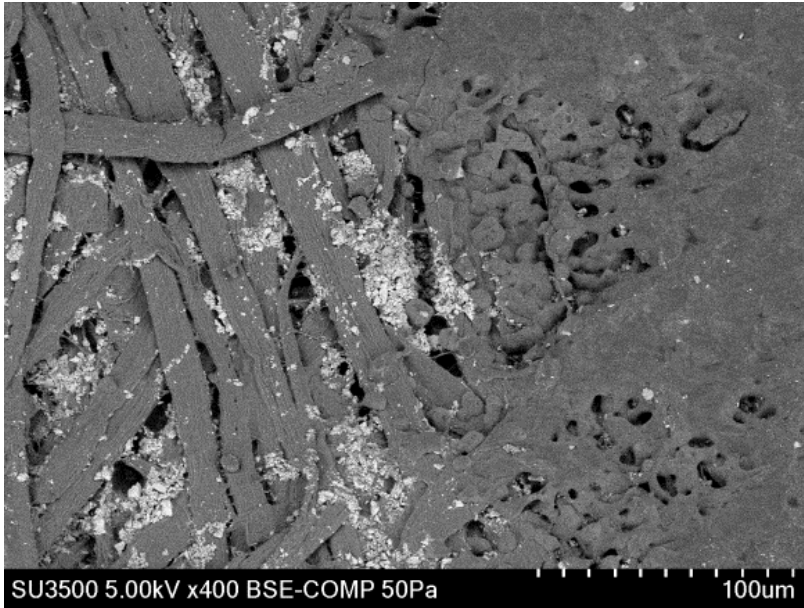
**BSE COMPO**



**BSE 3D**

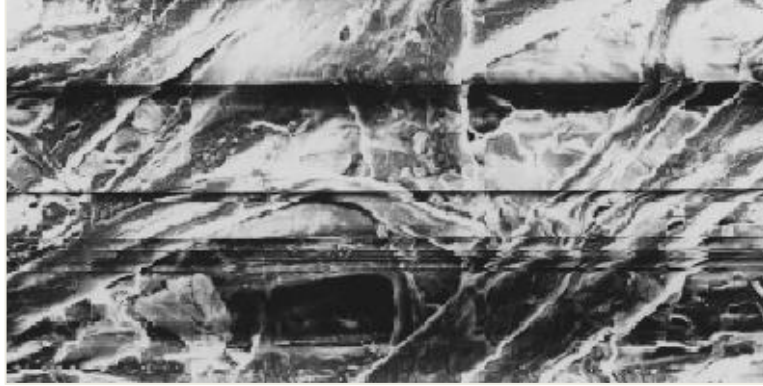


# UVD Dedektörü

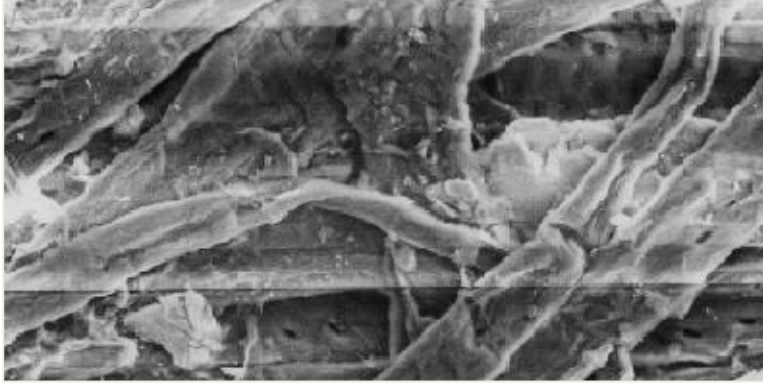




Pressure:  
**5 Pa**



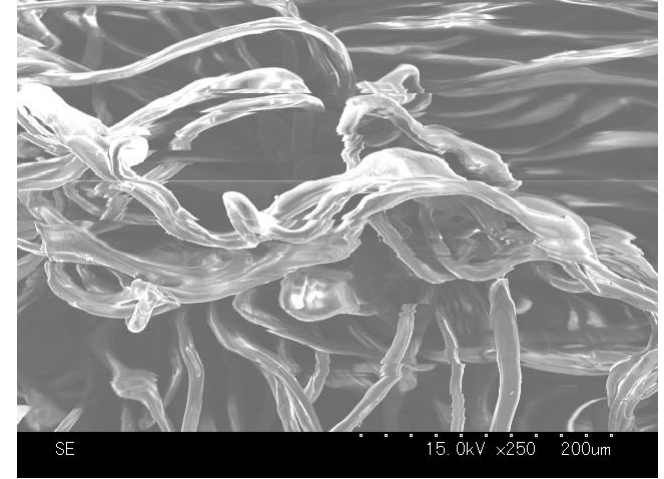
Pressure:  
**10 Pa**



Pressure:  
**20 Pa**



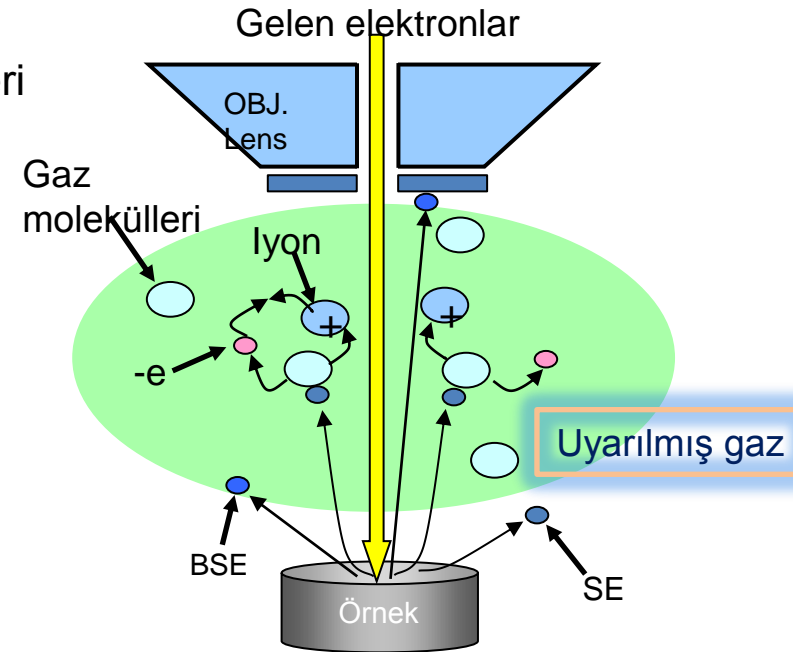
**Kaplanmamış**



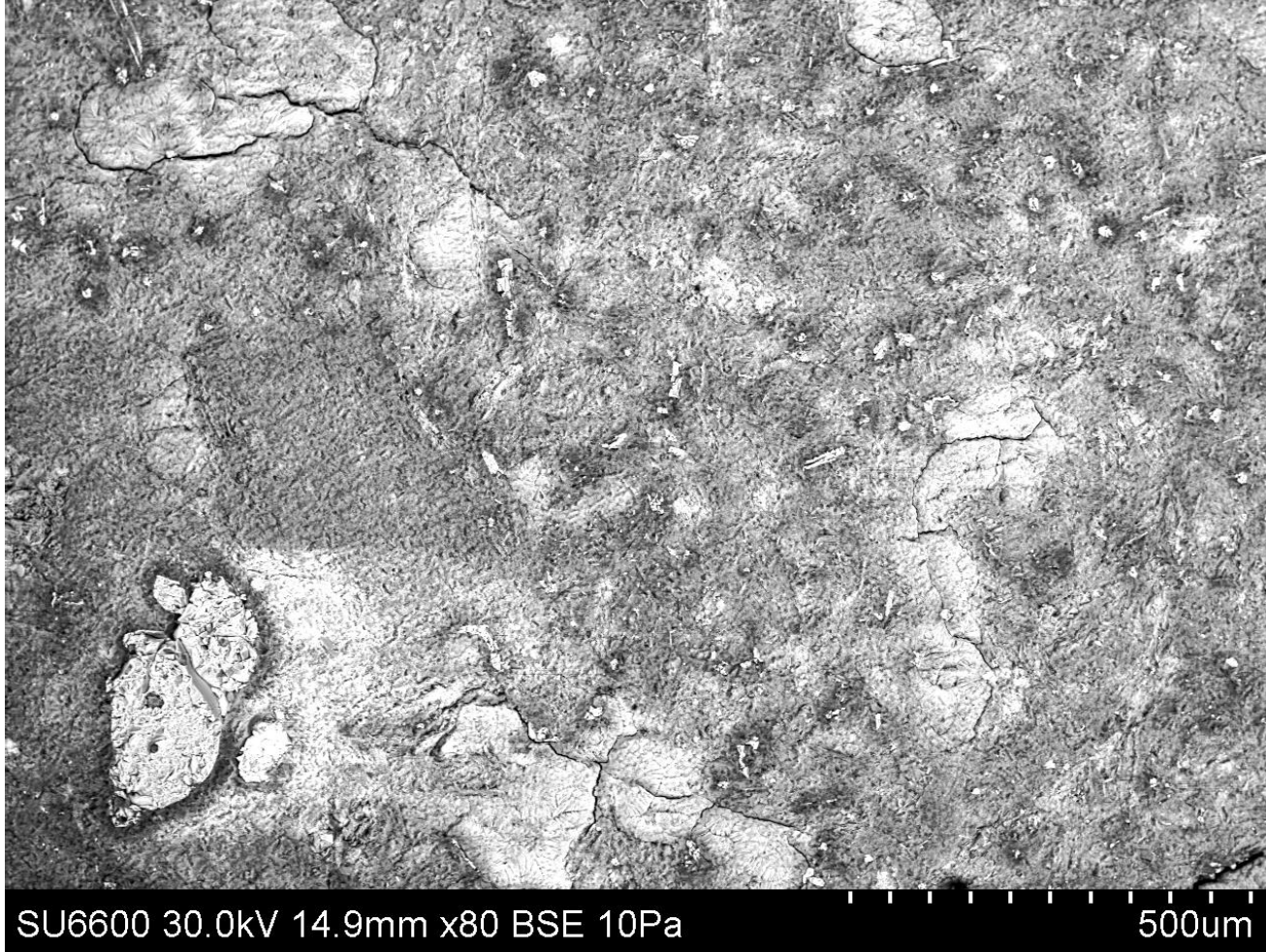
**Kaplanmış**



- Yüksek Vakum Modu (İletken örnekler)
- Düşük Vakum Modu (Yalıtkan örnekler)
- Charging etkisini kaldırmak için iyonize gaz molekülleri

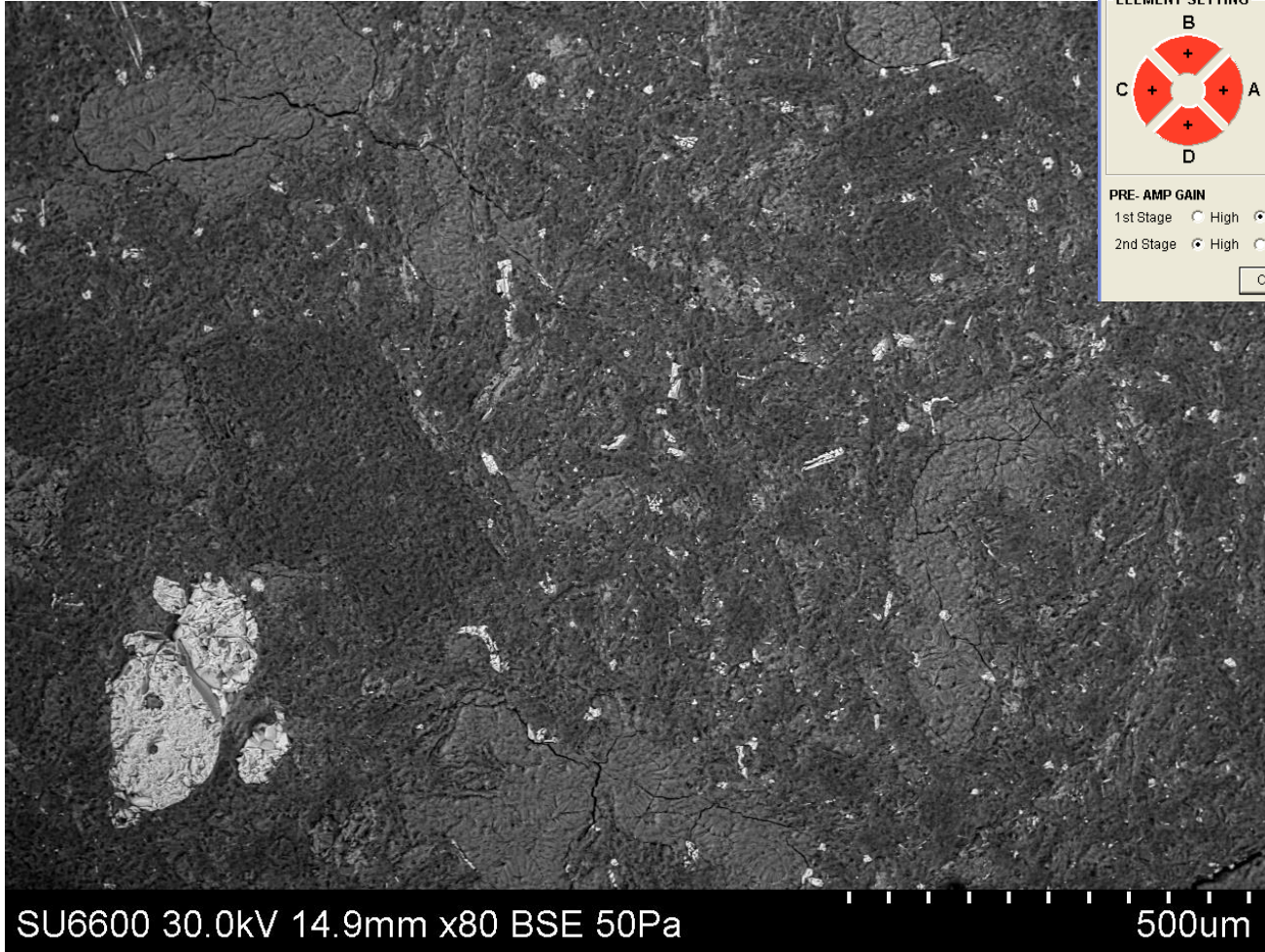






Bazalt - kaplanmamıř

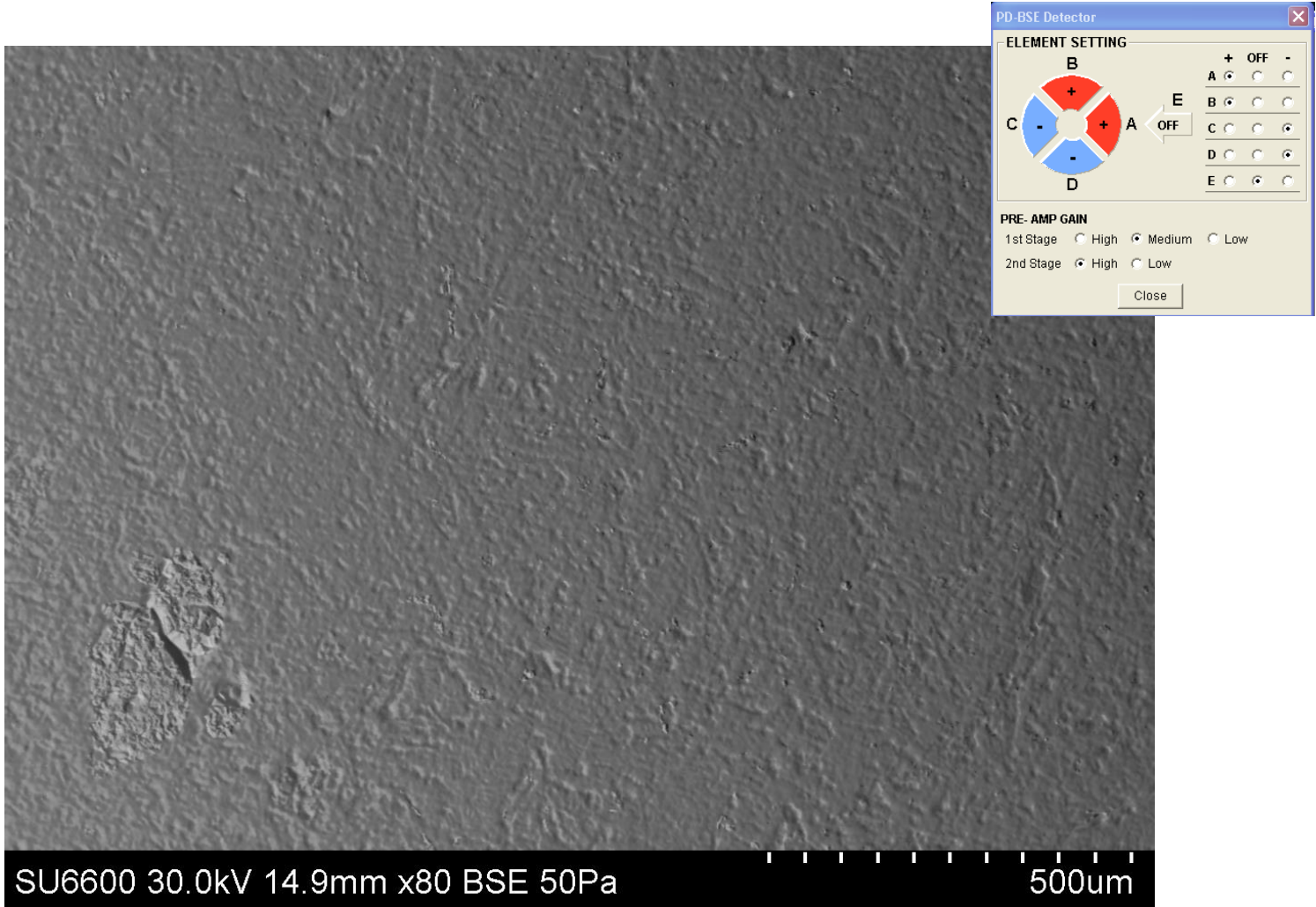




SU6600 30.0kV 14.9mm x80 BSE 50Pa

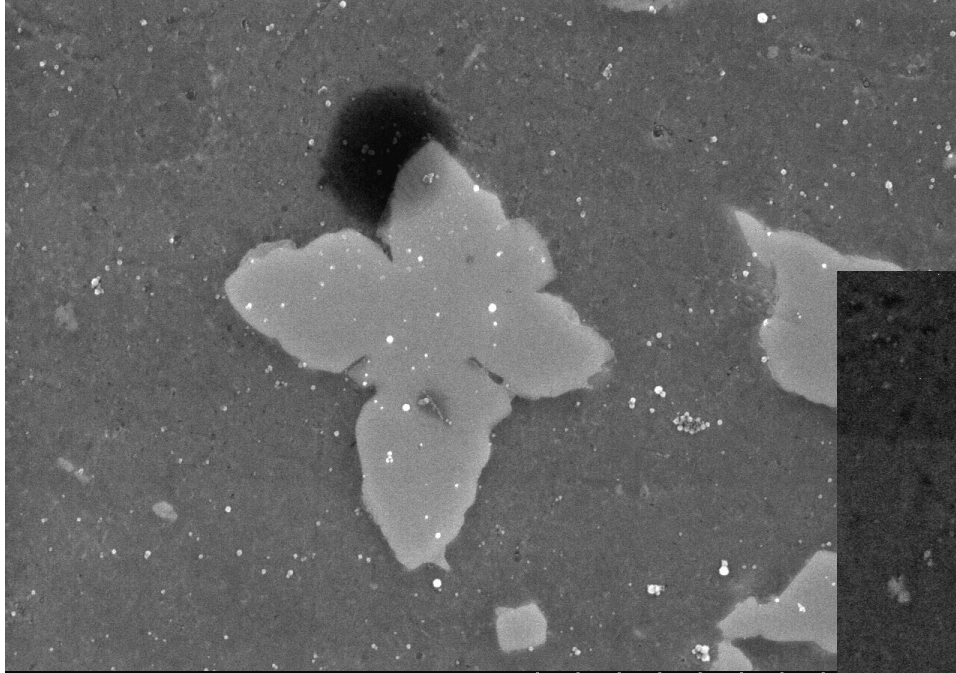
500um

Bazalt - kaplanmamış

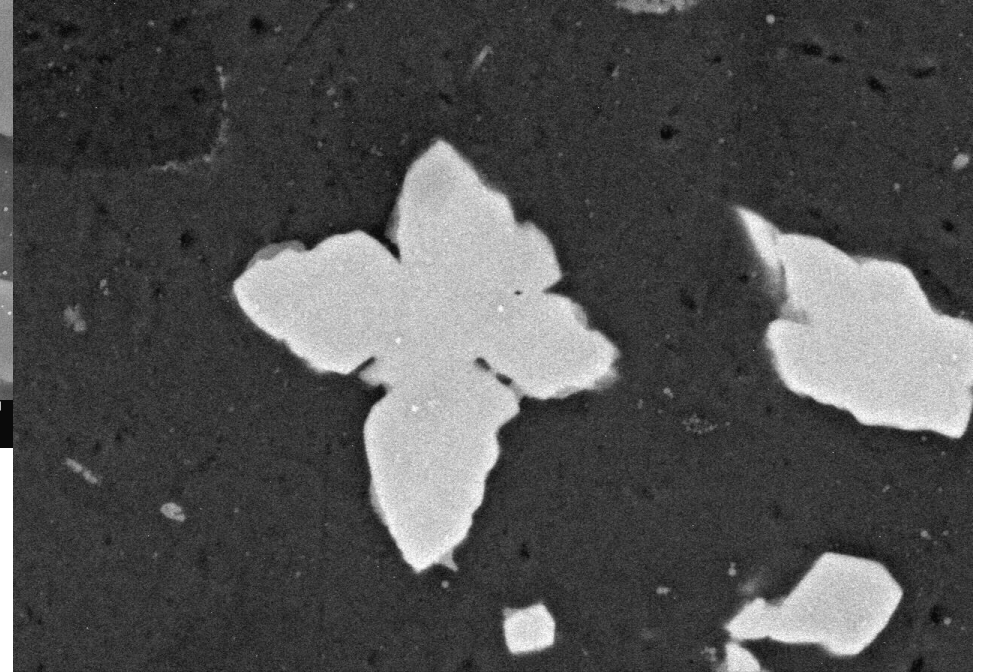


Bazalt - kaplanmamış



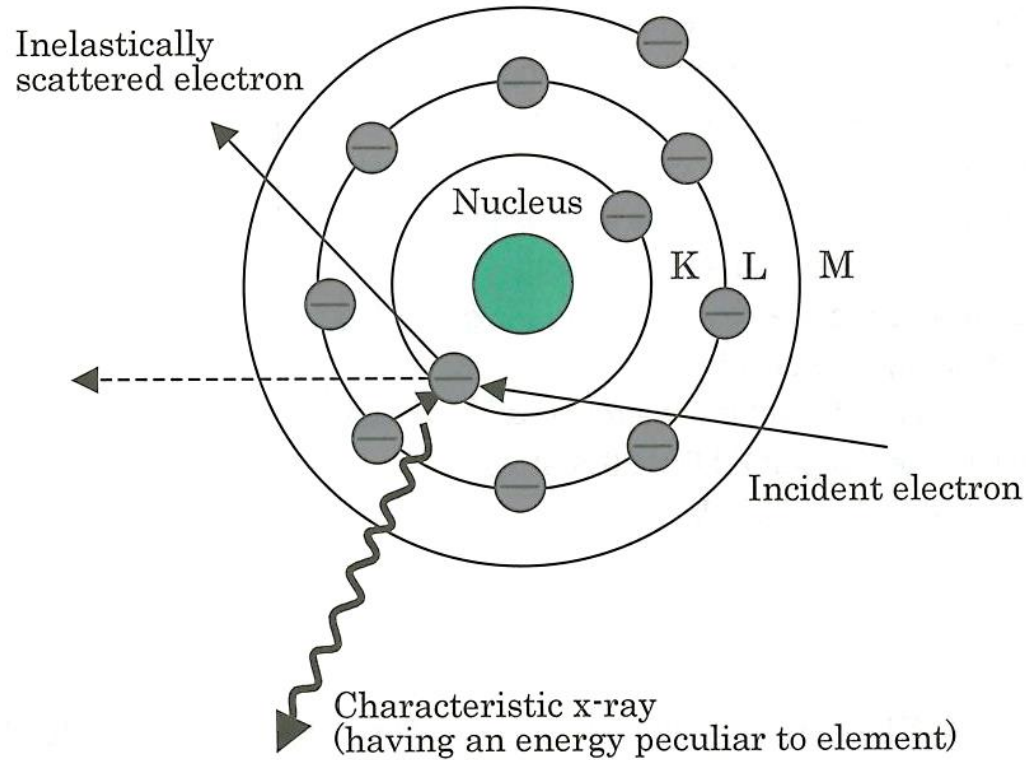


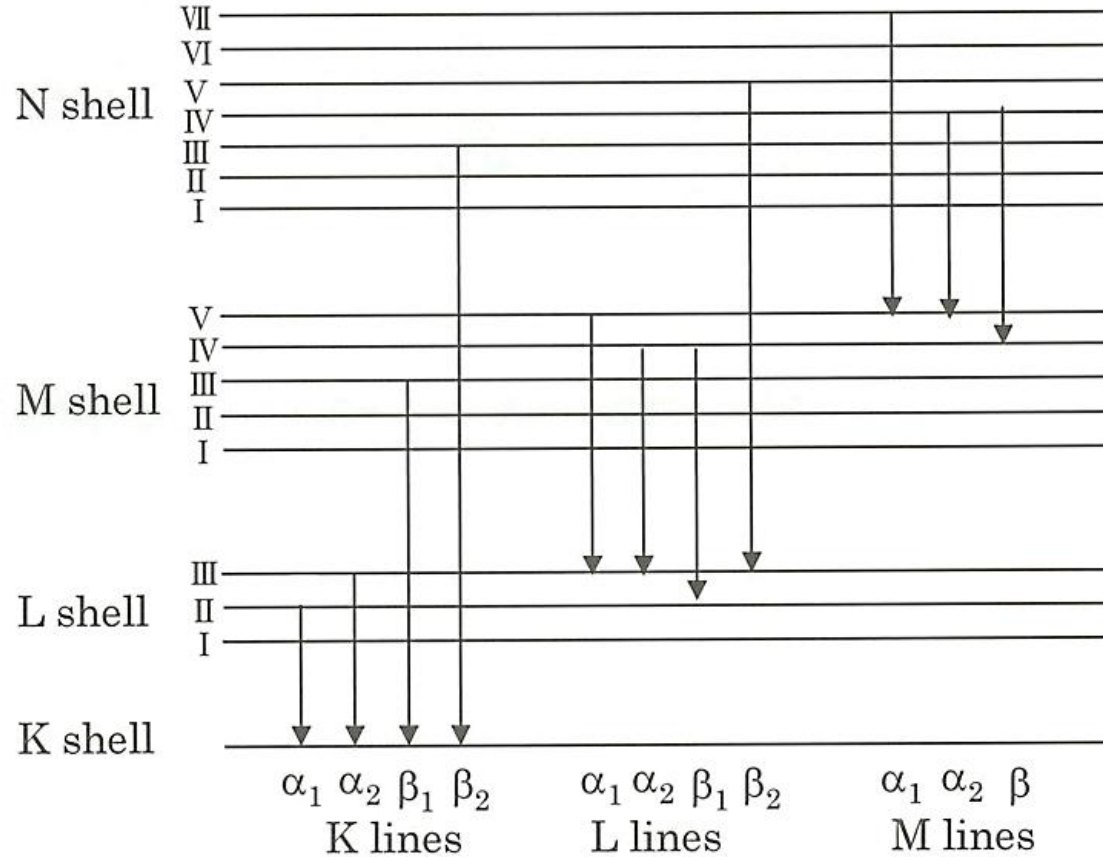
S4800 5.0kV 6.5mm x18.0k SE(U, LAO) 7/5/2006 12:43



S4800 5.0kV 6.5mm x18.0k YAGBSE 7/5/2006 12:43

3.00um







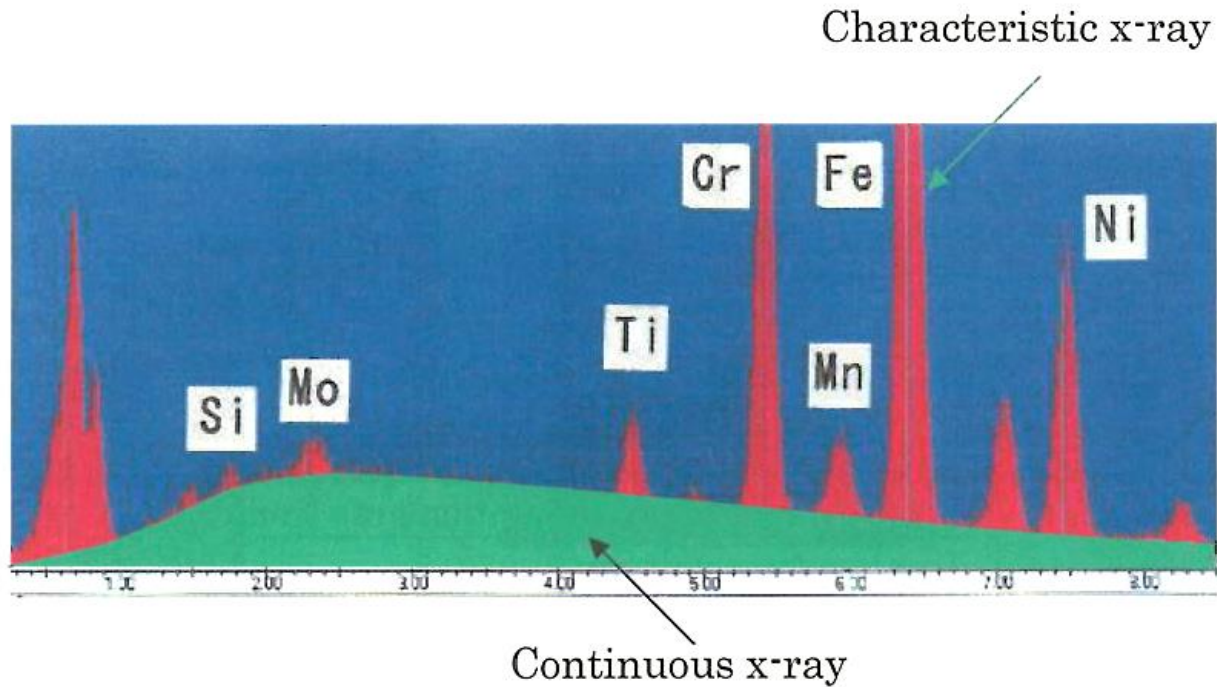
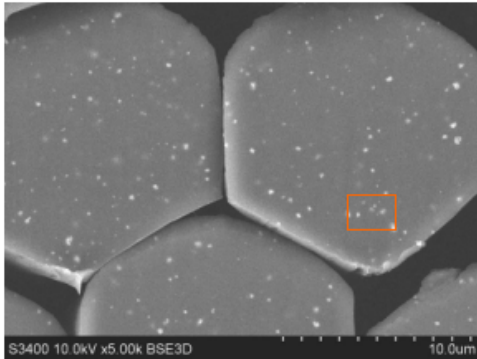
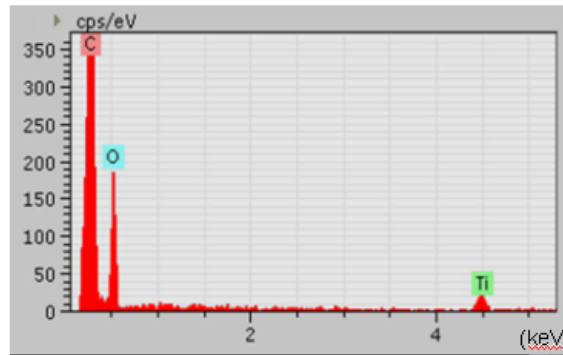


Fig. 3 X-ray Spectrum of Stainless Steel Specimen with Energy-dispersive X-ray Spectrometer

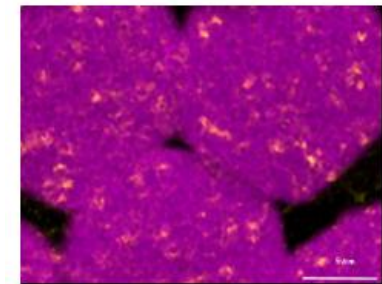


## Backscattered electron image (× 5,000 magnification)

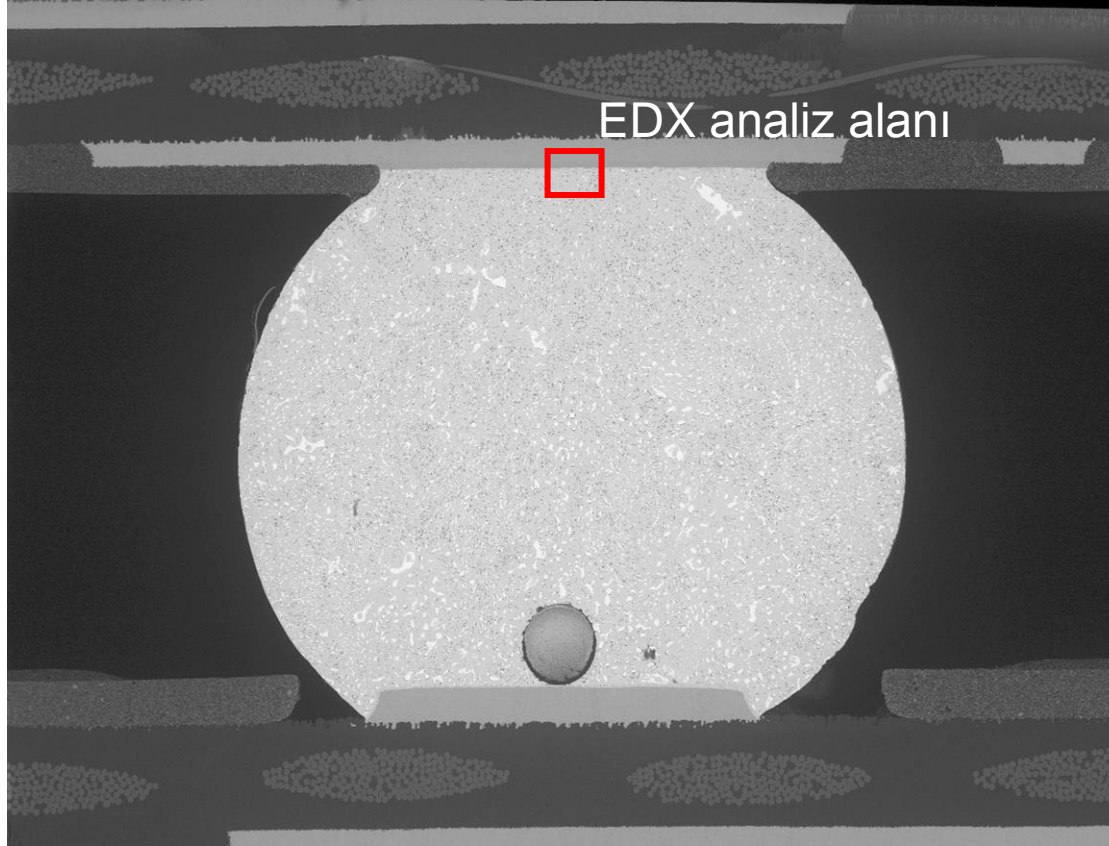
The cross-sectional structure of the fiber was observed with a backscattered electron detector. This permits conformation of how the white particles are dispersed in the fiber.



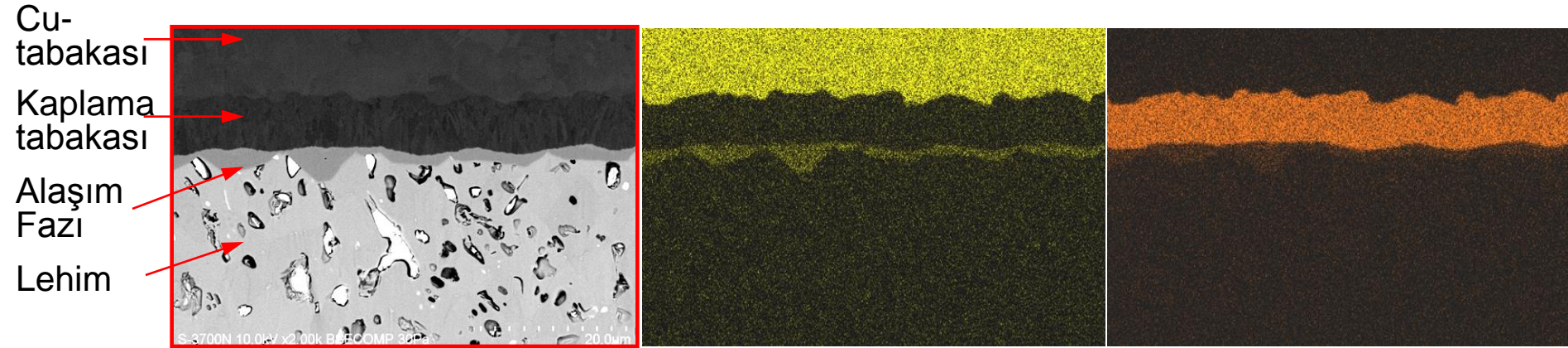
X-ray spectrum of area enclosed in rectangle above



**C Ti** X-ray mapping image of C and Ti



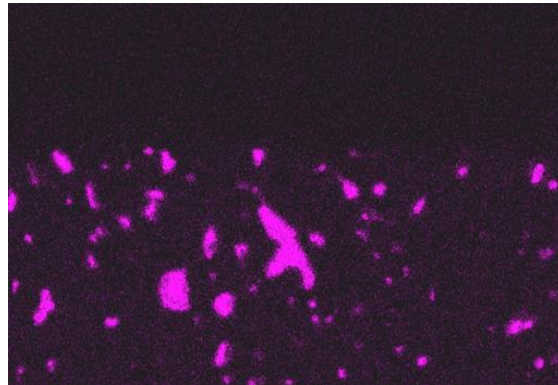




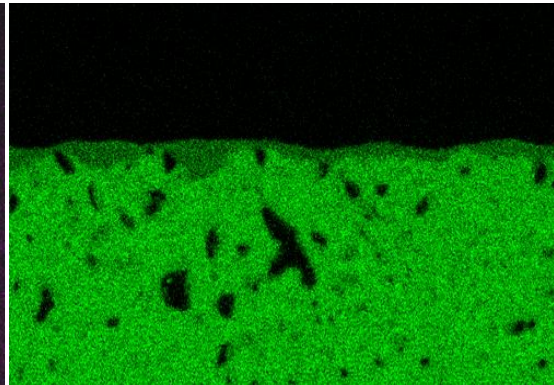
BSE görüntüsü (compo)

Cu-K

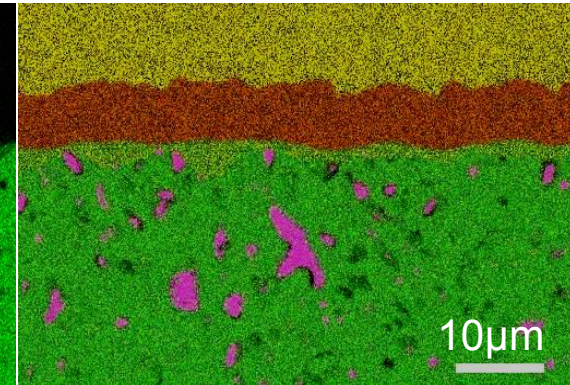
Ni-K



Pb-M



Sn-L

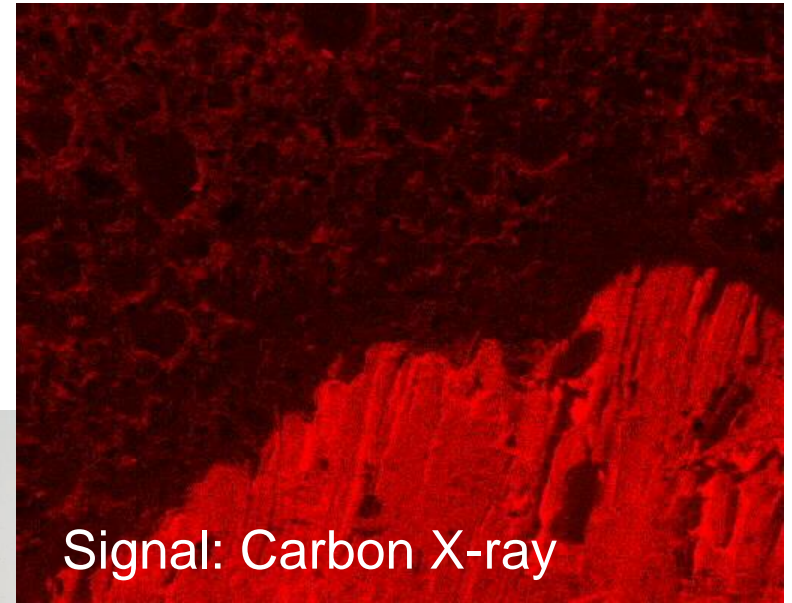
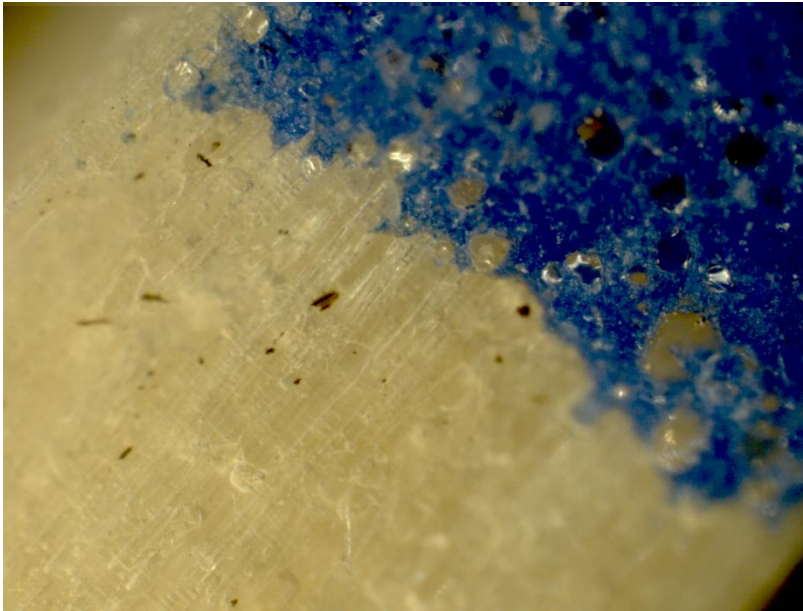


4 elementin üst üste gösterimi

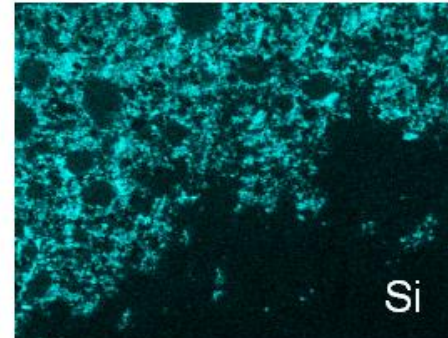
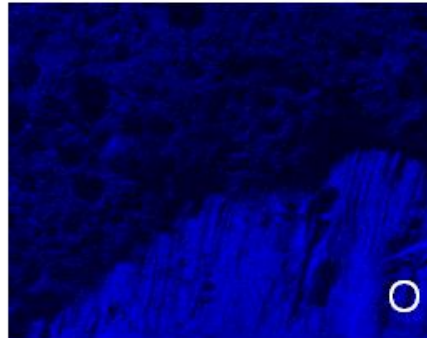
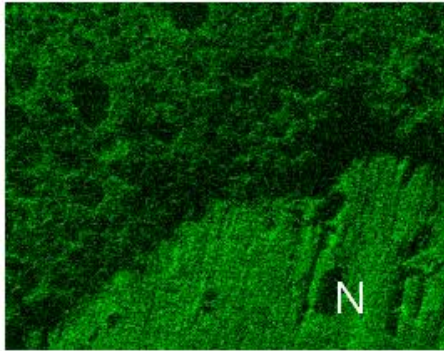
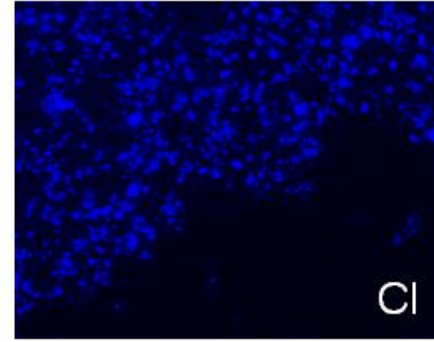
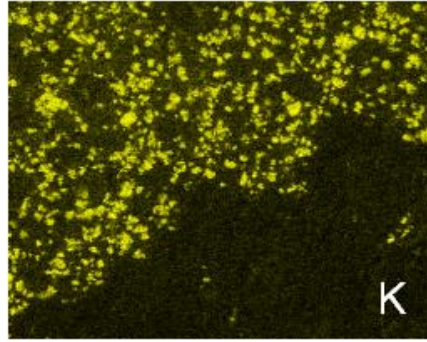
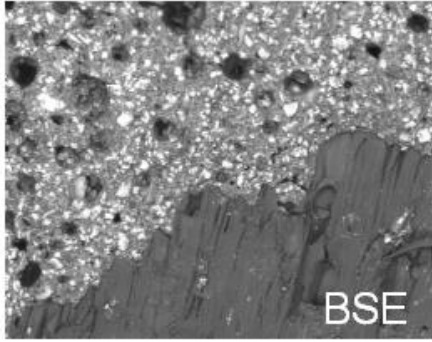
Vacc. : 15kV

Mag. : x2k

Integration time : 3min







- Teşekkürler...